



P-Channel Enhancement Mode Field Effect Transistor

Product Summary

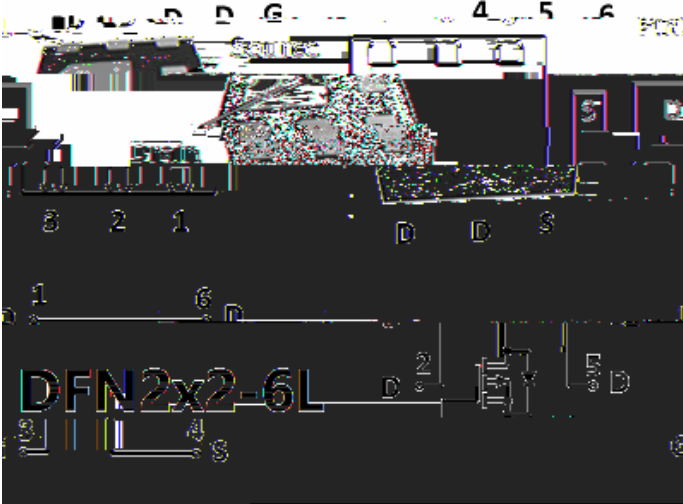
| | |
|------------------------------------|----------|
| V_{DS} | -20V |
| I_D | -7A |
| $R_{DS(ON)}$ (at $V_{GS}=-4.5V$) | 36.5mohm |
| $R_{DS(ON)}$ (at $V_{GS}=-2.5V$) | 46.5mohm |
| $R_{DS(ON)}$ (at $V_{GS}=-1.8V$) | 60.5mohm |

General Description

Trench Power LV MOSFET technology
High density cell design for Low $R_{DS(ON)}$
High Speed switching

Applications

Battery protection
Power management
Load switch



Absolute Maximum Ratings ($T_A=25$ unless otherwise noted)

| Parameter | Symbol | Maximum | Unit |
|---|----------|-------------------------|------|
| Drain-source Voltage | V_{DS} | -20 | V |
| Gate-source Voltage | V_{GS} | ± 10 | V |
| Drain Current | I_D | $T_C=25$ @ Steady State | -7 |
| | | $T_C=70$ @ Steady State | -5.6 |
| Pulsed Drain Current ^A | I_{DM} | -28 | A |
| Total Power Dissipation @ $T_C=25$ ^C | P_D | 2.2 | W |

Thermal Resistance Junction-to-Ambient @ Steady State ^D R_{JA}

Ordering Information (Example)

| PREFERRED P/N | PACKING CODE | Marking | MINIMUM PACKAGE(pcs) | INNER BOX QUANTITY(pcs) | OUTER CARTON QUANTITY(pcs) | DELIVERY MODE |
|---------------|--------------|---------|----------------------|-------------------------|----------------------------|---------------|
| YJQ4666B | F1 | ..G66B | 3000 | 30000 | 120000 | 7 " reel |



Electrical Characteristics ($T_J=25$

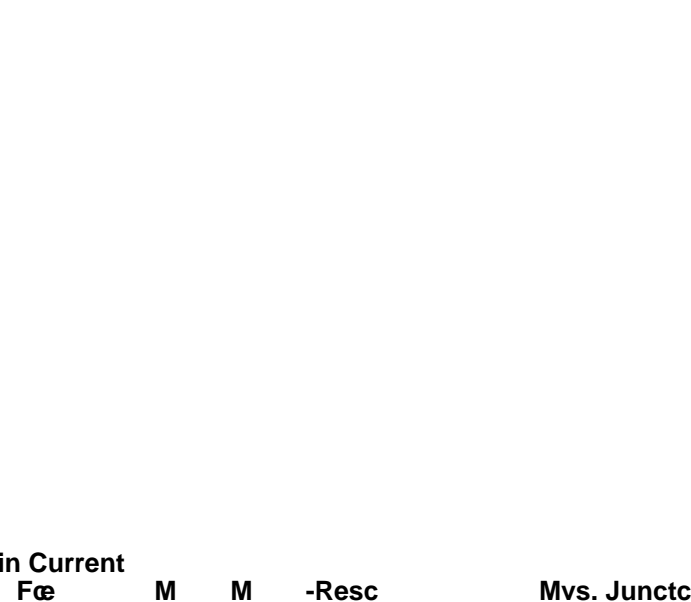
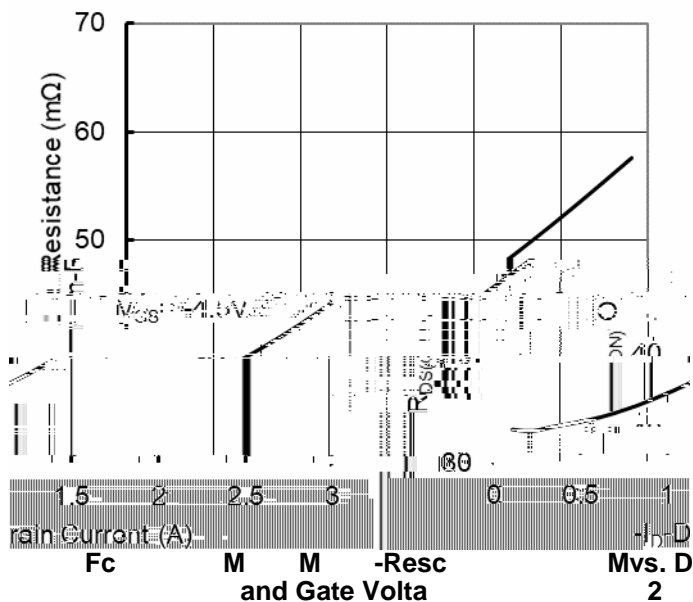
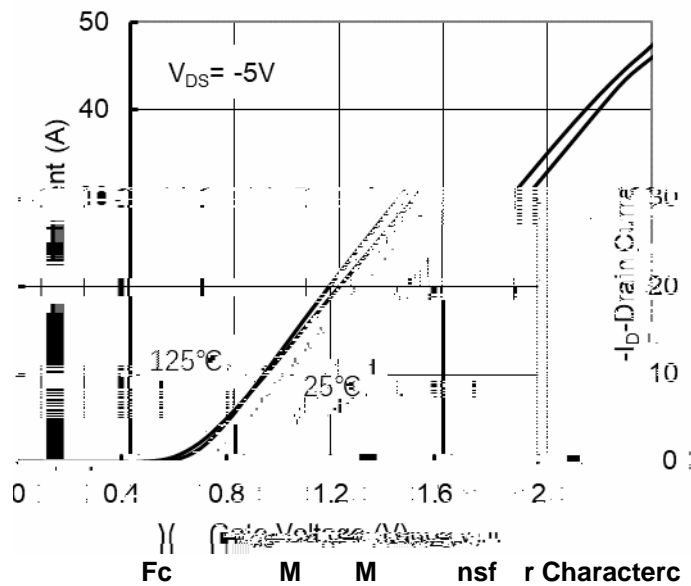
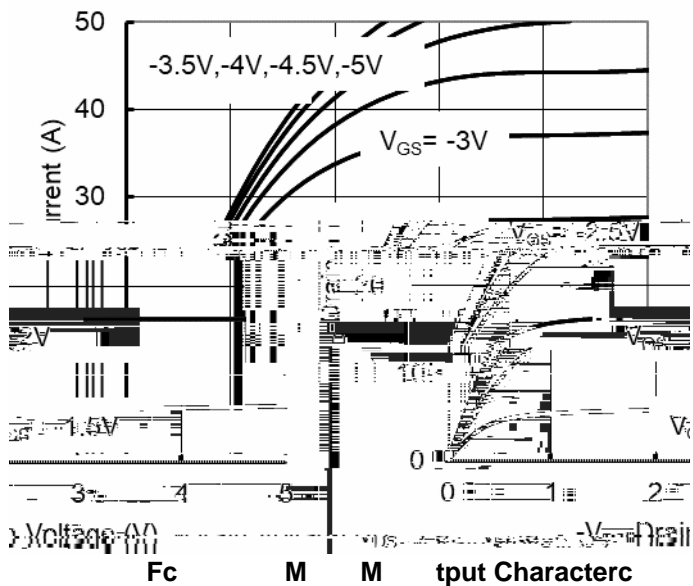
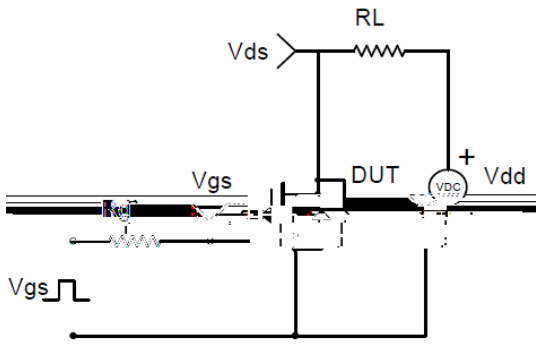


Figure 5. Capacitance Characteristics

Figure 6. Gate Charge







YJQ4666B

Disclaimer

The information presented in this document is for reference only. Yangzhou Yangjie Electronic Technology Co., Ltd. reserves the right to make changes without notice for the specification of the products displayed herein to improve reliability, function or design or otherwise.

The product listed herein is designed to be used with ordinary electronic equipment or devices, and not designed to be used with equipment or devices which require high level of reliability and the malfunction of which would directly endanger human life (such as medical instruments, etc.).